				Docket Number (Optional) 1382/005	Application Number				
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pk		5,93	39,886	08/17/99	Turner	et al.			
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pl		EP (0 878 824 A2	11/18/98	European Patent Office		·		
pL		021	87025	07/23/90	Japan				
pL	_	1114	45067	05/28/99	Japan				
pl		112	04509	07/30/99	Japan				
pl		112	65878	09/28/99	Japan				
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pt	Ph.F. Winters and J. W. Coburn,"Etching of Silicon with XeF2 Vapor," App. Phy. Lett., Vol. 34, No. 1, pp. 70-73, Jan. 1979.								o. 70-73, Jan. 1979.
ph	S.J. Sherman, W.K. Tsang, T.A. Core, D.E. Quinn,, "A Low Cost Monolithic Accelerometer," 1992 Symposium on VLSI Circuits, Digest of Technical Papers, Seattle, WA, USA, pp. 34-35, June 4-6, 1992.						osium on VLSI		
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pt	-	P.B. Chu, J.T. Chen, R. Difluoride," Transduce	Yeh, G. Lin, J.C.I rs 1997, Chicago, I	L, pp. 10	B.A. Warneke, and 6-19, June 1997.	K.S.J. Pister,	'Controlled Pulse-	Etening With	Xenon	
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